				
Notice of Allowability	Application No.		Applicant(s)	
	10/072,805	72,805 KAZUMORI, HIROYOSHI		OSHI
	Examiner		Art Unit	
	Paul Gurzo		2881	
The MAILING DATE of this communication apperature All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS or other appro IGHTS. This a	 S) CLOSED in this appopriate communication application is subject to 	olication. If not include will be mailed in due	ed course. THIS
 This communication is responsive to 9/15/03. The allowed claim(s) is/are 1-11. The drawings filed on are accepted by the Examine Acknowledgment is made of a claim for foreign priority und a) All Some* C) None of the: 	der 35 U.S.C. §			
1. Certified copies of the priority documents have				
 Certified copies of the priority documents have Copies of the certified copies of the priority documents. International Bureau (PCT Rule 17.2(a)). * Certified copies not received:				ion from the
5. Acknowledgment is made of a claim for domestic priority ur (a) The translation of the foreign language provisional a 6. Acknowledgment is made of a claim for domestic priority ur	pplication has	been received.	onal application).	
Applicant has THREE MONTHS FROM THE "MAILING DATE" of below. Failure to timely comply will result in ABANDONMENT of the complete of the comple	this communion	cation to file a reply co n. THIS THREE-MON	mplying with the requ ITH PERIOD IS NOT	irements noted EXTENDABLE.
7. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which gives reas	itted. Note the on(s) why the	attached EXAMINER' oath or declaration is o	'S AMENDMENT or N deficient.	IOTICE OF
 8. CORRECTED DRAWINGS must be submitted. (a) including changes required by the Notice of Draftspers 1) hereto or 2) to Paper No. (b) including changes required by the proposed drawing of including changes required by the attached Examiner 	correction filed	, which has be	en approved by the E	
Identifying indicia such as the application number (see 37 CFR 1. each sheet.	84(c)) should b	e written on the drawin	gs in the front (not the	back) of
 DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT FOR TI 	sit of BIOLOC HE DEPOSIT	SICAL MATERIAL m OF BIOLOGICAL MAT	nust be submitted. N FERIAL.	lote the
Attachment(s)				
 Notice of References Cited (PTO-892) Notice of Draftperson's Patent Drawing Review (PTO-948) Information Disclosure Statements (PTO-1449), Paper No	·	2☐ Notice of Informa 4☐ Interview Summa 6☐ Examiner's Amer 8☒ Examiner's State 9☐ Other	ary (PTO-413), Paper adment/Comment	No

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DETAILED ACTION

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Allowable Subject Matter

Claims 1-11 are allowed.

The following is an examiner's statement of reasons for allowance: As the claimed invention was read in light of the specification, the prior art of record fails to disclose or render obvious a scanning electron microscope and method of detecting electrons produced from a specimen in a scanning electron microscope having an inner polepiece, an outer polepiece, an objective lens forming a magnetic lens field leaking onto a surface of a specimen located under lower end surfaces of the polepieces, the objective lens acting to focus an electron beam onto the specimen, a first opening formed in the inner polepiece and located above the lower end surface of the inner polepiece, and a secondary electron detector mounted outside the inner polepiece to detect secondary electrons passed through the first opening, wherein a negative voltage is applied to the specimen to produce a decelerating electric field near the surface of the specimen to decelerate the electron beam, wherein there is provided a conversion electrode on which secondary electrons emitted from the specimen impinge, the conversion electrode being mounted around an electron beam passage inside the objective lens, and wherein secondary electrons emitted from said conversion electrode are guided via said first opening to said secondary electron detector and detected.

The closest prior art, Ose et al. and Takaoka et al., teach the use of an inner and outer polepiece, objective lens, secondary electron detector, negative voltage application, and conversion electrode. However, they are silent about the claimed openings in the polepieces and a conversion electrode mounted around an electron beam inside the objective lens.

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Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Paul Gurzo whose telephone number is (703) 306-0532. The examiner can normally be reached on M-Thurs. 7:30 - 6:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Lee can be reached on (703) 308-4116. The fax phone numbers for the organization where this application or proceeding is assigned are (703) 872-9318 for regular communications and (703) 872-9319 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

PMG October 29, 2003

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